

# FGH40N60SMDF 600V, 40A Field Stop IGBT

#### Features

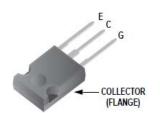
- Maximum Junction Temperature : T<sub>J</sub> =175°C
- Positive Temperaure Co-efficient for easy parallel operating
- High current capability
- Low saturation voltage:  $V_{CE(sat)} = 1.9V(Typ.) @ I_C = 40A$
- · High input impedance
- Fast switching
- Tighten Parameter Distribution
- RoHS compliant

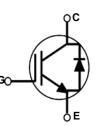
#### **Applications**

- Solar Inverter, UPS, SMPS, PFC
- Induction Heating

## **General Description**

Using Novel Field Stop IGBT Technology, Fairchild's new series of Field Stop IGBTs offer the optimum performance for Solar Inverter, UPS, SMPS, IH and PFC applications where low conduction and switching losses are essential.





### **Absolute Maximum Ratings**

| Symbol              | Description  |                                       | Ratings     | Units |  |
|---------------------|--|---------------------------------------|-------------|-------|--|
| V <sub>CES</sub>    | Collector to Emitter Voltage   |                                       | 600         | V     |  |
| V <sub>GES</sub>    | Gate to Emitter Voltage  |                                       | ± 20        | V     |  |
| I <sub>C</sub>      | Collector Current  | @ T <sub>C</sub> = 25°C               | 80          | A     |  |
|                     | Collector Current  | @ T <sub>C</sub> = 100 <sup>o</sup> C | 40          | A     |  |
| I <sub>CM (1)</sub> | Pulsed Collector Current   |                                       | 120         | A     |  |
| I <sub>F</sub>      | Diode Forward Current  | @ T <sub>C</sub> = 25°C               | 40          | A     |  |
|                     | Diode Forward Current  | @ T <sub>C</sub> = 100 <sup>o</sup> C | 20          | A     |  |
| I <sub>FM (1)</sub> | Pulsed Diode Maximum Forward Current                                       |                                       | 120         | A     |  |
| P <sub>D</sub>      | Maximum Power Dissipation  | @ T <sub>C</sub> = 25°C               | 349         | W     |  |
| . D                 | Maximum Power Dissipation  | @ T <sub>C</sub> = 100 <sup>o</sup> C | 174         | W     |  |
| TJ                  | Operating Junction Temperature   |                                       | -55 to +175 | °C    |  |
| T <sub>stg</sub>    | Storage Temperature Range  |                                       | -55 to +175 | °C    |  |
| Τ <sub>L</sub>      | Maximum Lead Temp. for soldering<br>Purposes, 1/8" from case for 5 seconds |                                       | 300         | °C    |  |

#### Notes:

1: Repetitive rating: Pulse width limited by max. junction temperature

**March 2011** 

### Thermal Characteristics

| Symbol                  | Parameter                               | Тур. | Max. | Units |
|-------------------------|---|------|------|-------|
| $R_{\theta JC}$ (IGBT)  | Thermal Resistance, Junction to Case    | -    | 0.43 | °C/W  |
| $R_{\theta JC}$ (Diode) | Thermal Resistance, Junction to Case    | -    | 1.45 | °C/W  |
| $R_{\thetaJA}$          | Thermal Resistance, Junction to Ambient | -    | 40   | °C/W  |

# Package Marking and Ordering Information

| Device Marking | Device       | Package | Reel Size | Tape Width | Quantity |
|----------------|--------------|---------|-----------|------------|----------|
| FGH40N60SMDF   | FGH40N60SMDF | TO-247  | -         | -          | 30       |

# Electrical Characteristics of the IGBT $T_{C} = 25^{\circ}C$ unless otherwise noted

| Symbol                                 | Parameter                                    | Test Conditions  | Min. | Тур. | Max. | Units |
|--|--|--|------|------|------|-------|
| Off Charac                             | teristics                                    |  |      |      |      |       |
| BV <sub>CES</sub>                      | Collector to Emitter Breakdown Voltage       | $V_{GE} = 0V, I_{C} = 250 \mu A$                                     | 600  | -    | -    | V     |
| $\frac{\Delta BV_{CES}}{\Delta T_{J}}$ | Temperature Coefficient of Breakdown Voltage | $V_{GE} = 0V, I_{C} = 250\mu A$                                      | -    | 0.6  | -    | V/ºC  |
| I <sub>CES</sub>                       | Collector Cut-Off Current                    | $V_{CE} = V_{CES}, V_{GE} = 0V$                                      | -    | -    | 250  | μA    |
| I <sub>GES</sub>                       | G-E Leakage Current                          | $V_{GE} = V_{GES}, V_{CE} = 0V$                                      | -    | -    | ±400 | nA    |
| On Charac                              | teristics                                    |  |      |      |      |       |
| V <sub>GE(th)</sub>                    | G-E Threshold Voltage                        | I <sub>C</sub> = 250μA, V <sub>CE</sub> = V <sub>GE</sub>            | 3.5  | 4.5  | 6.0  | V     |
|  |  | $I_{\rm C} = 40$ A, $V_{\rm GE} = 15$ V                              | -    | 1.9  | 2.5  | V     |
| V <sub>CE(sat)</sub>                   |  |  | -    | 2.1  | -    | V     |
| Dynamic C                              | haracteristics                               |  |      |      |      |       |
| Cies                                   | Input Capacitance                            |  | -    | 1880 | -    | pF    |
| C <sub>oes</sub>                       | Output Capacitance                           | V <sub>CE</sub> = 30V <sub>,</sub> V <sub>GE</sub> = 0V,<br>f = 1MHz | -    | 180  | -    | pF    |
| C <sub>res</sub>                       | Reverse Transfer Capacitance                 |  | -    | 50   | -    | pF    |
| Switching                              | Characteristics                              |  |      |      |      |       |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                           |  | -    | 12   | 16   | ns    |
| t <sub>r</sub>                         | Rise Time                                    |  | -    | 20   | 28   | ns    |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                          | V <sub>CC</sub> = 400V, I <sub>C</sub> = 40A,                        | -    | 92   | 120  | ns    |
| t <sub>f</sub>                         | Fall Time                                    | R <sub>G</sub> = 6Ω, V <sub>GE</sub> = 15V,                          | -    | 13   | 17   | ns    |
| Eon                                    | Turn-On Switching Loss                       | Inductive Load, $T_C = 25^{\circ}C$                                  | -    | 1.3  | 2.0  | mJ    |
| E <sub>off</sub>                       | Turn-Off Switching Loss                      |  | -    | 0.26 | 0.34 | mJ    |
| E <sub>ts</sub>                        | Total Switching Loss                         |  | -    | 1.56 | 2.34 | mJ    |
| t <sub>d(on)</sub>                     | Turn-On Delay Time                           |  | -    | 15   | -    | ns    |
| t <sub>r</sub>                         | Rise Time                                    | 1  | -    | 22   | -    | ns    |
| t <sub>d(off)</sub>                    | Turn-Off Delay Time                          | V <sub>CC</sub> = 400V, I <sub>C</sub> = 40A,                        | -    | 116  | -    | ns    |
| t <sub>f</sub>                         | Fall Time                                    | $R_{G} = 6\Omega, V_{GE} = 15V,$                                     | -    | 16   | -    | ns    |
| Eon                                    | Turn-On Switching Loss                       | Inductive Load, T <sub>C</sub> = 175 <sup>o</sup> C                  | -    | 2.1  | -    | mJ    |
| E <sub>off</sub>                       | Turn-Off Switching Loss                      | ]  | -    | 0.6  | -    | mJ    |
| E <sub>ts</sub>                        | Total Switching Loss                         | 1  | -    | 2.7  | -    | mJ    |

# Electrical Characteristics of the IGBT (Continued)

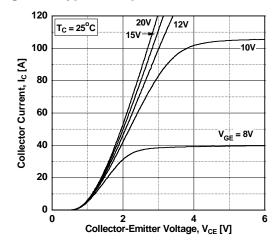
| Symbol          | Parameter                | Test Conditions  | Min. | Тур. | Max | Units |
|-----------------|--------------------------|--|------|------|-----|-------|
| Qg              | Total Gate Charge        |  | -    | 119  | 180 | nC    |
| Q <sub>ge</sub> | Gate to Emitter Charge   | V <sub>CE</sub> = 400V, I <sub>C</sub> = 40A,<br>V <sub>GE</sub> = 15V | -    | 13   | 20  | nC    |
| Q <sub>gc</sub> | Gate to Collector Charge | VGE - 10V  | -    | 58   | 90  | nC    |

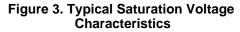
# Electrical Characteristics of the Diode $T_{C} = 25^{\circ}C$ unless otherwise noted

| Symbol                     | Parameter                     | Test Conditions                                    |                                     | Min. | Тур. | Max | Units |
|----------------------------|-------------------------------|--|-------------------------------------|------|------|-----|-------|
| V <sub>FM</sub>            | Diode Forward Voltage         | I <sub>F</sub> = 20A                               | $T_C = 25^{\circ}C$                 | -    | 1.3  | 1.7 | V     |
| VFM Diode i olward voltage | 1F - 20A                      | T <sub>C</sub> = 175°C                             | -                                   | 1.15 | -    |     |       |
| E <sub>rec</sub>           | Reverse Recovery Energy       |  | $T_{\rm C} = 175^{\rm o}{\rm C}$    | -    | 138  | -   | uJ    |
| t <sub>rr</sub>            | Diode Reverse Recovery Time   | I <sub>F</sub> =20A, dI <sub>F</sub> /dt = 200A/μs | $T_{\rm C} = 25^{\rm o}{\rm C}$     | -    | 70   | 100 | ns    |
| ٩r                         |                               | $F = 207$ , $G = 2007/\mu^3$                       | T <sub>C</sub> = 175 <sup>o</sup> C | -    | 210  | -   |       |
| Q <sub>rr</sub>            | Diode Reverse Recovery Charge |  | $T_{\rm C} = 25^{\rm o}{\rm C}$     | -    | 250  | 350 | nC    |
| α <sub>II</sub>            | Diodo Novoloo Novoloj enalgo  |  | $T_{C} = 175^{\circ}C$              | -    | 1875 | -   |       |

### **Typical Performance Characteristics**

#### **Figure 1. Typical Output Characteristics**





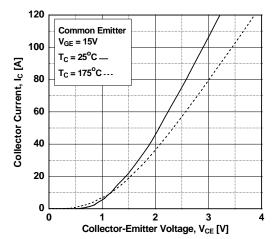
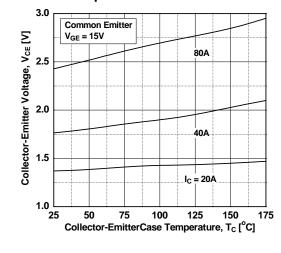
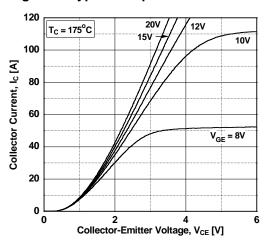


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level



**Figure 2. Typical Output Characteristics** 



**Figure 4. Transfer Characteristics** 

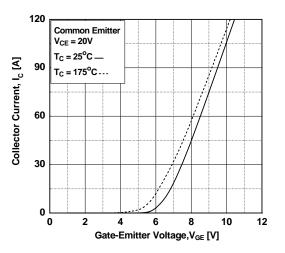
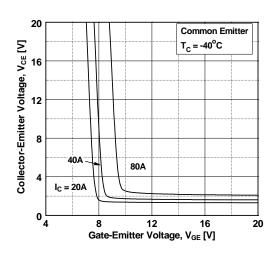
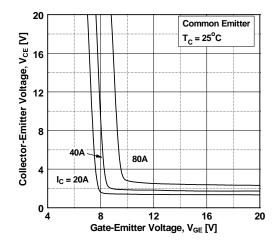


Figure 6. Saturation Voltage vs. V<sub>GE</sub>



### **Typical Performance Characteristics**

#### Figure 7. Saturation Voltage vs. V<sub>GE</sub>





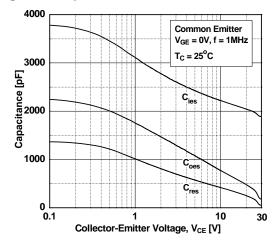


Figure 11. SOA Characteristics

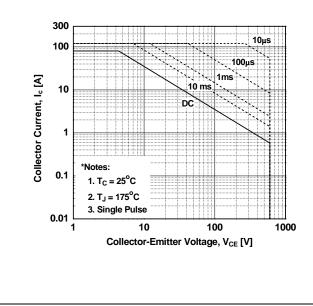


Figure 8. Saturation Voltage vs. V<sub>GE</sub>

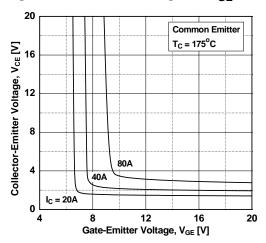


Figure 10. Gate charge Characteristics

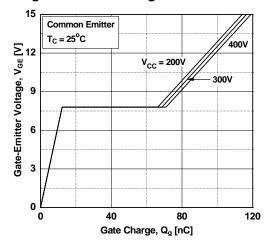
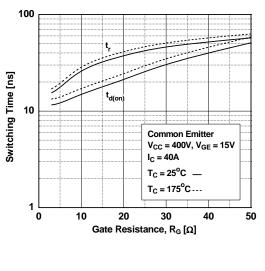
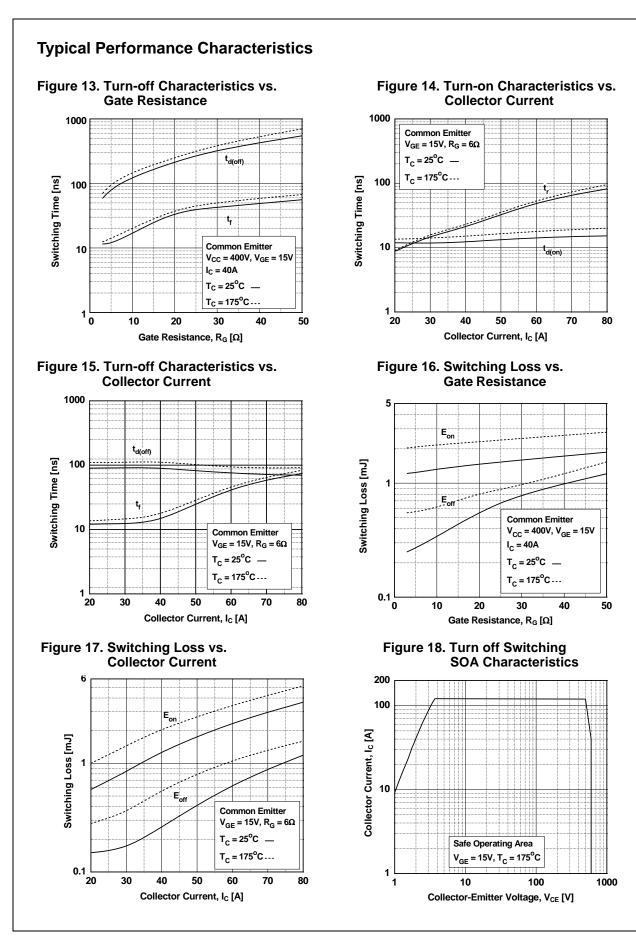


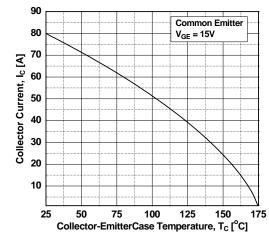
Figure 12. Turn-on Characteristics vs. Gate Resistance



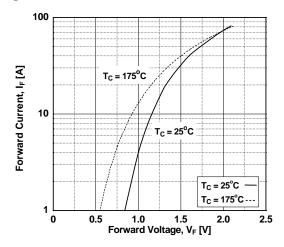


# Typical Performance Characteristics

#### Figure 19. Current Derating









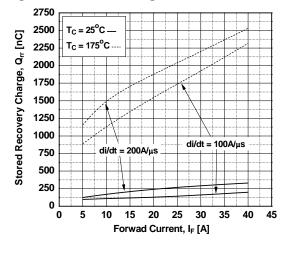
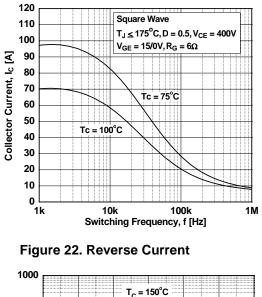


Figure 20. Load Current Vs. Frequency



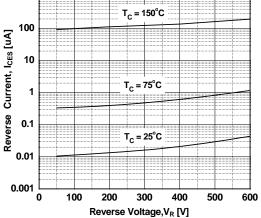
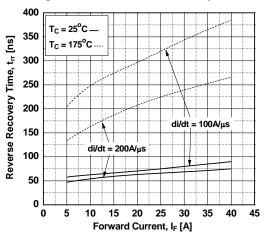
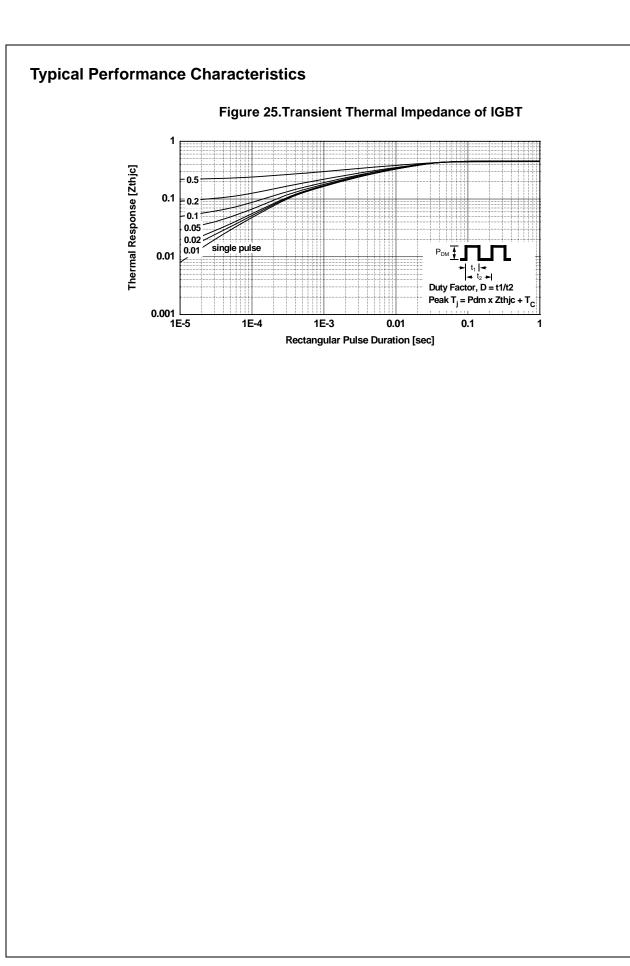
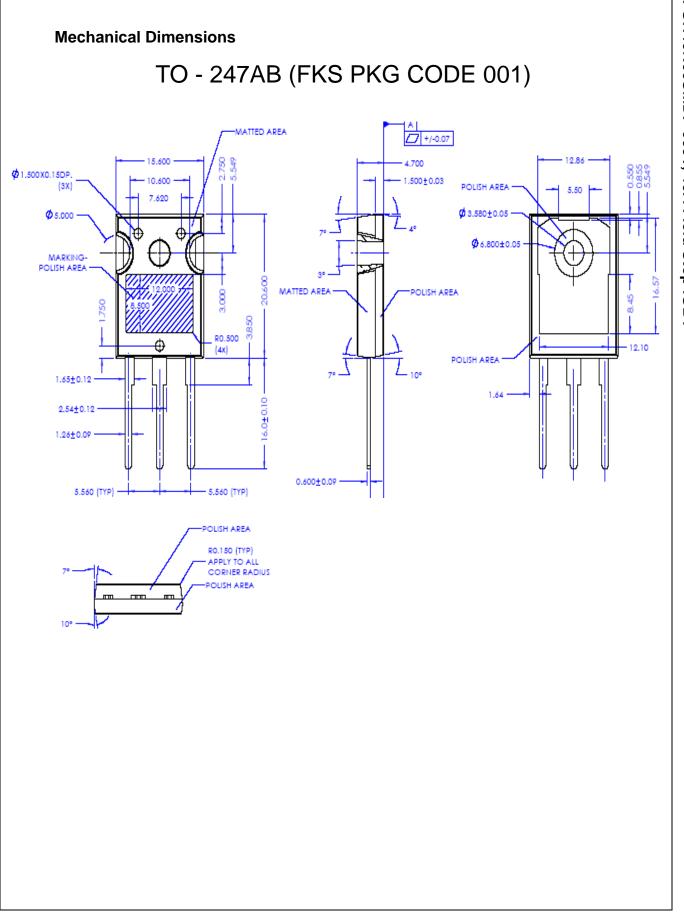
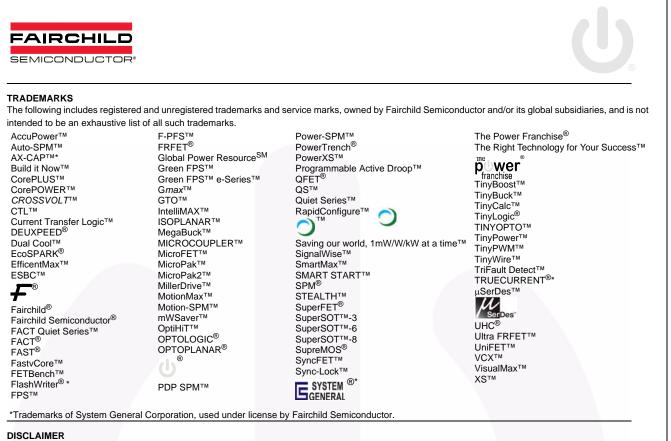


Figure 24. Reverse Recovery Time









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